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1 M SRAM (128-kword \times 8-bit)

HITACHI

ADE-203-996 (Z) Preliminary, Rev. 0.0 Jan. 20, 1999

Description

The Hitachi HM628128D Series is 1-Mbit static RAM organized 131,072-kword × 8-bit. HM628128D Series has realized higher density, higher performance and low power consumption by employing Hi-CMOS process technology. The HM628128D Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has package variations of standard 32-pin plastic DIP, standard 32-pin plastic SOP and standard 32-pin plastic TSOPI.

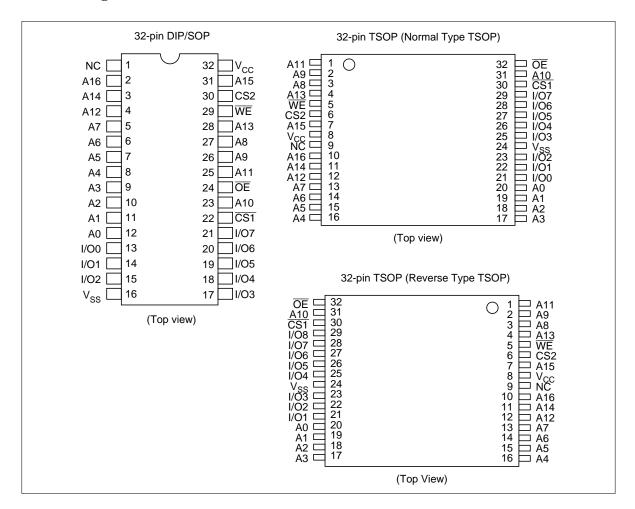
Features

- Single 5 V supply: 5 V ± 10%
 Access time: 55 ns/70 ns (max)
- · Power dissipation
 - Active: 30 mW/MHz (typ)
 - Standby: 10 μW (typ)
- Completely static memory.
 - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output
 - Three state output
- Directly TTL compatible all inputs
- Battery backup operation
 - 2 chip selection for battery backup

Ordering Information

| Type No. | Access time | Package |
|--------------------------------------|----------------|---|
| HM628128DLP-5 HM628128DLP-7 | 55 ns 70 ns | 600-mil 32-pin plastic DIP (DP-32) |
| HM628128DLP-5SL HM628128DLP-7SL | 55 ns 70 ns | |
| HM628128DLP-5UL HM628128DLP-7UL | 55 ns 70 ns | |
| HM628128DLFP-5 HM628128DLFP-7 | 55 ns 70 ns | 525-mil 32-pin plastic SOP (FP-32D) |
| HM628128DLFP-5SL HM628128DLFP-7SL | 55 ns 70 ns | |
| HM628128DLFP-5UL HM628128DLFP-7UL | 55 ns 70 ns | |
| HM628128DLTS-5 HM628128DLTS-7 | 55 ns 70 ns | $8 \times 13.4 \text{ mm } 32\text{-pin plastic TSOP I (TFP-32DC)}$ |
| HM628128DLTS-5SL HM628128DLTS-7SL | 55 ns 70 ns | |
| HM628128DLTS-5UL HM628128DLTS-7UL | 55 ns 70 ns | |
| HM628128DLT-5 HM628128DLT-7 | 55 ns 70 ns | Normal-bend type 8 × 20 mm 32-pin plastic TSOP I (TFP-32D) |
| HM628128DLT-5SL HM628128DLT-7SL | 55 ns 70 ns | |
| HM628128DLT-5UL HM628128DLT-7UL | 55 ns 70 ns | |
| HM628128DLR-5 HM628128DLR-7 | 55 ns 70 ns | Reverse-bend type 8 × 20 mm 32-pin plastic TSOP I (TFP-32DR) |
| HM628128DLR-5SL HM628128DLR-7SL | 55 ns 70 ns | |
| HM628128DLR-5UL HM628128DLR-7UL | 55 ns 70 ns | |

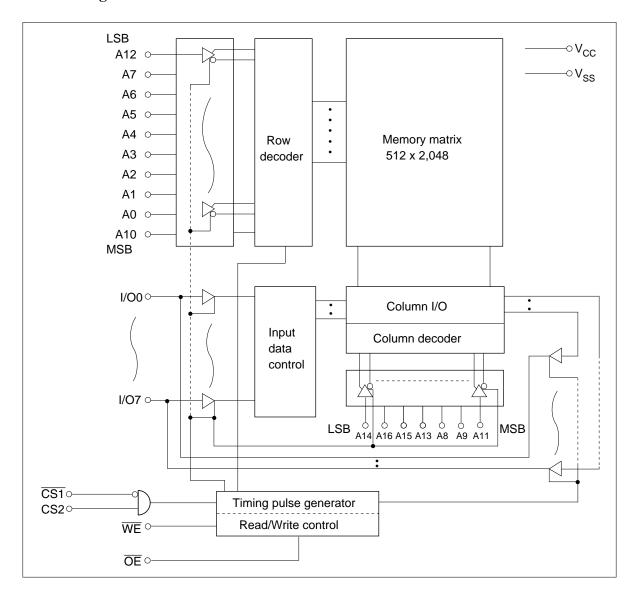
Pin Arrangement



Pin Description

| Pin name | Function |
|-----------------|-------------------|
| A0 to A16 | Address input |
| I/O0 to I/O7 | Data input/output |
| CS1 | Chip select 1 |
| CS2 | Chip select 2 |
| WE | Write enable |
| ŌĒ | Output enable |
| V _{cc} | Power supply |
| V _{SS} | Ground |
| NC | No connection |

Block Diagram



Operation Table

| CS1 | CS2 | WE | OE | I/O | Operation | |
|-----|-----|----|----|--------|----------------|---|
| Н | Н | × | × | High-Z | Standby | _ |
| L | L | × | × | High-Z | Standby | |
| L | L | × | × | High-Z | Standby | |
| L | Н | Н | L | Dout | Read | |
| L | Н | L | Н | Din | Write | _ |
| L | Н | L | L | Din | Write | |
| L | Н | Н | Н | High-Z | Output disable | _ |

Note: H: V_{IH} , L: V_{IL} , \times : V_{IH} or V_{IL}

Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|-----------------|------------------------------------|------|
| Power supply voltage relative to V _{ss} | V _{cc} | -0.5 to +7.0 | V |
| Terminal voltage on any pin relative to V _{ss} | V _T | -0.5^{*1} to $V_{CC} + 0.3^{*2}$ | V |
| Power dissipation | P _T | 1.0 | W |
| Storage temperature range | Tstg | -55 to +125 | °C |
| Storage temperature range under bias | Tbias | -20 to +85 | °C |

Notes: 1. V_T min: -1.5 V for pulse half-width \leq 30 ns

2. Maximum voltage is +7.0 V

DC Operating Conditions

| Parameter | Symbol | Min | Тур | Max | Unit | Note |
|---------------------------|-----------------|------|-----|-----------------------|------|------|
| Supply voltage | V _{cc} | 4.5 | 5.0 | 5.5 | V | |
| | V _{SS} | 0 | 0 | 0 | V | |
| Input high voltage | V _{IH} | 2.2 | _ | V _{cc} + 0.3 | V | |
| Input low voltage | V _{IL} | -0.3 | _ | 0.8 | V | 1 |
| Ambient temperature range | Та | -20 | | +70 | °C | |

Note: 1. V_{IL} min: -1.5 V for pulse half-width ≤ 30 ns

DC Characteristics

| Parameter | Symbol | Min | Typ*1 | Max | Unit | Test conditions |
|---------------------------|------------------------|-----|-------|-----|------|--|
| Input leakage current | I _{Li} | _ | _ | 1 | μΑ | $Vin = V_{SS}$ to V_{CC} |
| Output leakage current | I _{LO} | | _ | 1 | μΑ | |
| Operating current | I _{cc} | _ | _ | 15 | mA | $\overline{CS1} = V_{IL}, CS2 = V_{IH},$ others = $V_{IH}/V_{IL}, I_{I/O} = 0 \text{ mA}$ |
| Average operating current | I _{cc1} | _ | _ | 60 | mA | $\begin{aligned} &\text{Min cycle, duty} = 100\% \\ &\text{I}_{\text{I/O}} = 0 \text{ mA, } \overline{\text{CS1}} = \text{V}_{\text{IL}}, \text{CS2} \\ &= \text{V}_{\text{IH}}, \text{Others} = \text{V}_{\text{IH}}/\text{V}_{\text{IL}} \end{aligned}$ |
| | I _{CC2} | _ | 6 | 20 | mA | $\begin{split} &\text{Cycle time} = 1 \; \mu\text{s}, \\ &\text{duty} = 100\%, \\ &\text{I}_{\text{I/O}} = 0 \; \text{mA}, \; \overline{\text{CS1}} \leq 0.2 \; \text{V}, \\ &\text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \\ &\text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \\ &\text{V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$ |
| Standby current | I _{SB} | _ | _ | 2 | mA | (1) $\overline{CS1} = V_{IH}$, $CS2 = V_{IH}$, or (2) $CS2 = V_{IL}$ |
| | *2 _{SB1} | _ | 2 | 100 | μΑ | 0 V \leq Vin (1) 0 V \leq CS2 \leq 0.2 V or (2) $\overline{\text{CS1}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V},$ $\text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \text{ V}$ |
| | I _{SB1} *3 | _ | 2 | 50 | μΑ | |
| | _{SB1} *4 | _ | 1 | 20 | μΑ | |
| Output high voltage | V _{OH} | 2.4 | _ | | V | $I_{OH} = -1 \text{ mA}$ |
| Output low voltage | V_{OL} | | _ | 0.4 | V | I _{OL} = 2.1 mA |

Notes: 1. Typical values are at $V_{cc} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

- 2. This characteristics is guaranteed only for L version.
- 3. This characteristics is guaranteed only for L-SL version.
- 4. This characteristics is guaranteed only for L-UL version.

Capacitance (Ta = +25°C, f = 1 MHz)

| Parameter | Symbol | Тур | Max | Unit | Test conditions | Note |
|--------------------------|------------------|-----|-----|------|------------------------|------|
| Input capacitance | Cin | _ | 8 | pF | Vin = 0 V | 1 |
| Input/output capacitance | C _{I/O} | _ | 10 | pF | V _{I/O} = 0 V | 1 |

Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics (Ta = -20 to +70 °C, V_{CC} = 5.0 V \pm 10%, unless otherwise noted.)

Test Conditions

• Input pulse levels: $V_{IL} = 0.8 \text{ V}, V_{IH} = 2.4 \text{ V}$

• Input rise and fall time: 5 ns

Input timing reference levels: 1.5 V
Output timing reference level: 1.5 V

• Output load: 1 TTL Gate+ CL (100 pF) (HM628128D-7)

1 TTL Gate+ CL (50 pF) (HM628128D-5)

(Including scope and jig)

Read Cycle

HM628128D

| | | -5 | | -7 | | | |
|--------------------------------------|-------------------|-----|--------------|-----|--------------|------|---------|
| Parameter | Symbol | Min | Max | Min | Max | Unit | Notes |
| Read cycle time | t _{RC} | 55 | _ | 70 | _ | ns | |
| Address access time | t _{AA} | _ | 55 | _ | 70 | ns | |
| Chip select access time | t _{ACS1} | _ | 55 | | 70 | ns | |
| | t _{ACS2} | _ | 55 | | 70 | ns | |
| Output enable to output valid | t _{OE} | _ | 30 | _ | 35 | ns | |
| Output hold from address change | t _{oH} | 10 | | 10 | | ns | |
| Chip selection to output in low-Z | t _{CLZ1} | 10 | _ | 10 | - | ns | 2, 3 |
| | t _{CLZ2} | 10 | _ | 10 | _ | ns | 2, 3 |
| Output enable to output in low-Z | t _{OLZ} | 5 | | 5 | | ns | 2, 3 |
| Chip deselection to output in high-Z | t _{CHZ1} | 0 | 20 | 0 | 25 | ns | 1, 2, 3 |
| | t _{CHZ2} | 0 | 20 | 0 | 25 | ns | 1, 2, 3 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 20 | 0 | 25 | ns | 1, 2, 3 |

Write Cycle

HM628128D

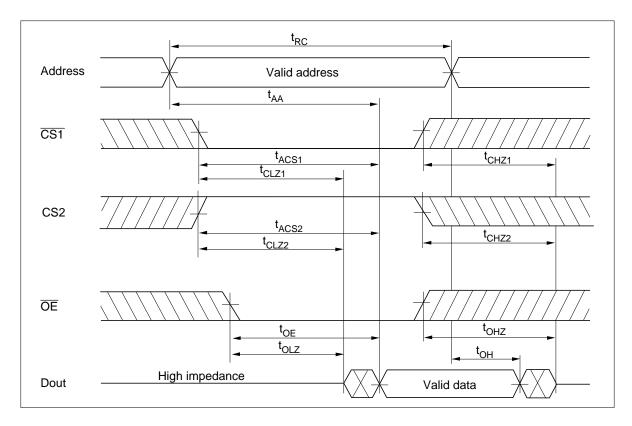
| | | -5 | | -7 | | | |
|-------------------------------------|------------------|-----|-------------|-----|-----|------|---------|
| Parameter | Symbol | Min | Max | Min | Max | Unit | Notes |
| Write cycle time | t _{wc} | 55 | _ | 70 | _ | ns | |
| Address valid to end of write | t _{AW} | 50 | _ | 60 | | ns | |
| Chip selection to end of write | t _{cw} | 50 | | 60 | _ | ns | 5 |
| Write pulse width | t _{wP} | 40 | _ | 50 | | ns | 4, 13 |
| Address setup time | t _{AS} | 0 | _ | 0 | | ns | 6 |
| Write recovery time | t _{wR} | 0 | | 0 | _ | ns | 7 |
| Data to write time overlap | t _{DW} | 20 | | 25 | _ | ns | |
| Data hold from write time | t _{DH} | 0 | _ | 0 | | ns | |
| Output active from output in high-Z | t _{ow} | 5 | | 5 | _ | ns | 2 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 20 | 0 | 25 | ns | 1, 2, 8 |
| WE to output in high-Z | t _{wHZ} | 0 | 20 | 0 | 25 | ns | 1, 2, 8 |

Notes: 1. t_{CHZ}, t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

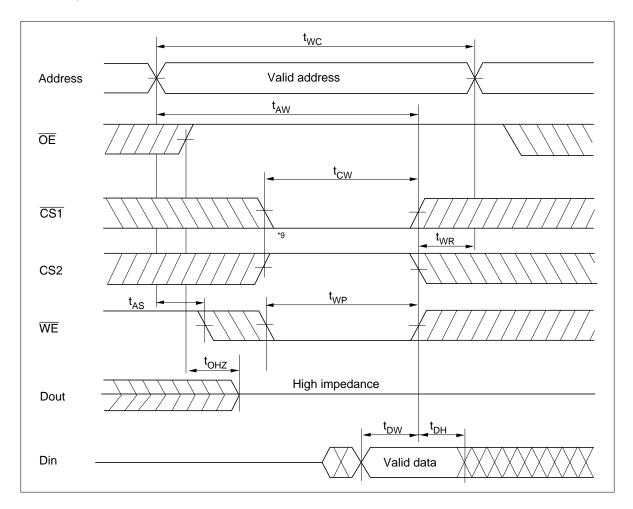
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition, t_{HZ} max is less than t_{LZ} min both for a given device and from device to device.
- 4. A write occurs during the overlap (t_{WP}) of a low $\overline{CS1}$, a high $\overline{CS2}$, and a low \overline{WE} . A write begins at the later transition of $\overline{CS1}$ going low, CS2 going high, or \overline{WE} going low. A write ends at the earlier transition of $\overline{CS1}$ going high, CS2 going low, or \overline{WE} going high. t_{WP} is measured from the beginning of write to the end of write.
- 5. t_{CW} is measured from $\overline{CS1}$ going low or CS2 going high to the end of write.
- 6. t_{AS} is measured from the address valid to the beginning of write.
- t_{wR} is measured from the earlier of WE or CS1 going high or CS2 going low to the end of write cycle.
- 8. During this period, I/O pins are in the output state; therefore, the input signals of the opposite phase to the outputs must not be applied.
- 9. If the $\overline{\text{CS1}}$ goes low or CS2 going high simultaneously with $\overline{\text{WE}}$ going low or after $\overline{\text{WE}}$ going low, the output remain in a high impedance state.
- 10. Dout is the same phase of the write data of this write cycle.
- 11. Dout is the read data of next address.
- 12. If $\overline{\text{CS1}}$ is low and CS2 high during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 13. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW}$ min + t_{WHZ} max

Timing Waveforms

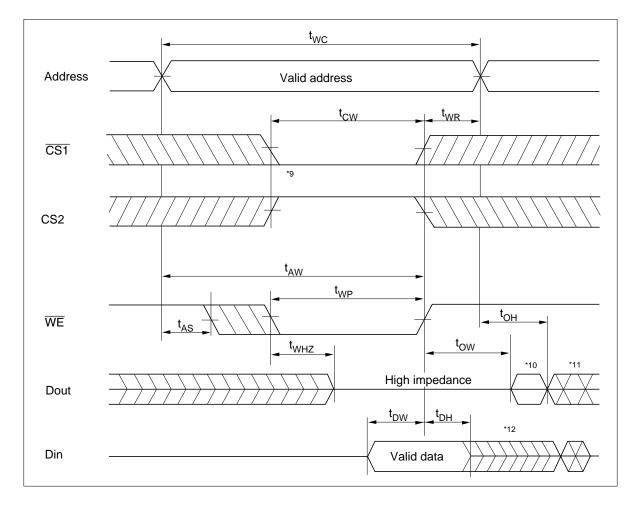
Read Cycle $(\overline{WE} = V_{IH})$



Write Cycle (1) $(\overline{OE} \operatorname{Clock})$



Write Cycle (2) $(\overline{OE} = V_{IL})$



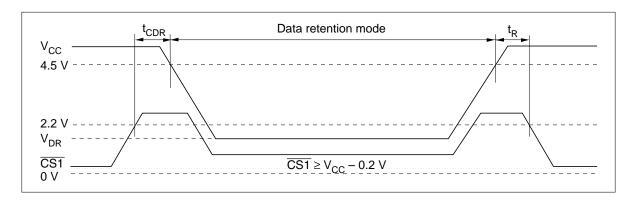
Low V_{CC} **Data Retention Characteristics** ($Ta = -20 \text{ to } +70^{\circ}\text{C}$)

| Parameter | Symbol | Min | Typ* ⁵ | Max | Unit | Test conditions*4 |
|--------------------------------------|----------------------|--------------------|-------------------|-----|------|---|
| V _{cc} for data retention | V_{DR} | 2.0 | _ | _ | V | Vin ≥ 0V (1) 0 V ≤ CS2 ≤ 0.2 V or (2) $\frac{\text{CS2}}{\text{CS1}}$ ≥ $\frac{\text{V}}{\text{CC}}$ − 0.2 V |
| Data retention current | I *1 CCDR | _ | 1.0 | 50 | μΑ | $\begin{array}{c} V_{\rm CC} = 3.0 \text{ V}, \text{ Vin } \geq 0 \text{ V} \\ \text{(1) } 0 \text{ V} \leq \text{CS2} \leq 0.2 \text{ V or} \\ \text{(2) } \frac{\text{CS2}}{\text{CS1}} \geq V_{\rm CC} - 0.2 \text{ V}, \\ \hline \hline \text{CS1} \geq V_{\rm CC} - 0.2 \text{ V} \end{array}$ |
| | I _{CCDR} *2 | _ | 1.0 | 15 | μΑ | |
| | I _{CCDR} *3 | _ | 0.5 | 10 | μΑ | |
| Chip deselect to data retention time | t_{CDR} | 0 | _ | _ | ns | See retention waveform |
| Operation recovery time | t _R | t _{RC} *6 | _ | _ | ns | |

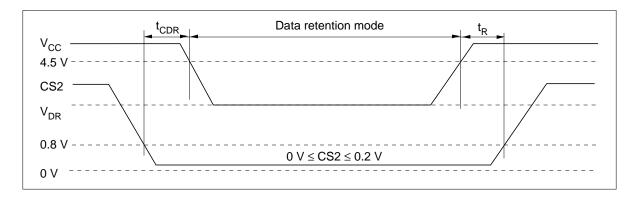
Notes: 1. This characteristic is guaranteed only for L-version, 20 μ A max. at Ta = -20 to +40°C.

- 2. This characteristic is guaranteed only for L-SL-version, 3 μ A max. at Ta = -20 to +40°C.
- 3. This characteristic is guaranteed only for L-UL-version, 1 μ A max. at Ta = -20 to +40°C.
- 4. CS2 controls address buffer, \overline{WE} buffer, $\overline{CS1}$ buffer, \overline{OE} buffer, and Din buffer. If CS2 controls data retention mode, Vin levels (address, \overline{WE} , \overline{OE} , $\overline{CS1}$, I/O) can be in the high impedance state. If $\overline{CS1}$ controls data retention mode, CS2 must be $CS2 \ge V_{CC} 0.2$ V or 0 V $\le CS2 \le 0.2$ V. The other input levels (address, \overline{WE} , \overline{OE} , I/O) can be in the high impedance state.
- 5. Typical values are at $V_{cc} = 3.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.
- 6. t_{RC} = read cycle time.

Low V_{CC} Data Retention Timing Waveform (1) ($\overline{CS1}$ Controlled)

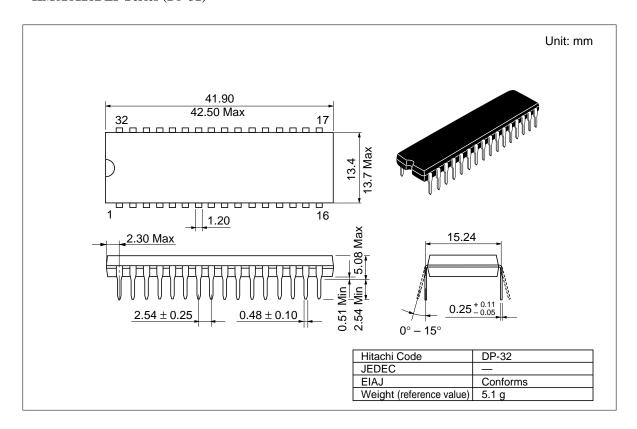


$Low~V_{CC}~Data~Retention~Timing~Waveform~(2)~(CS2~Controlled)\\$

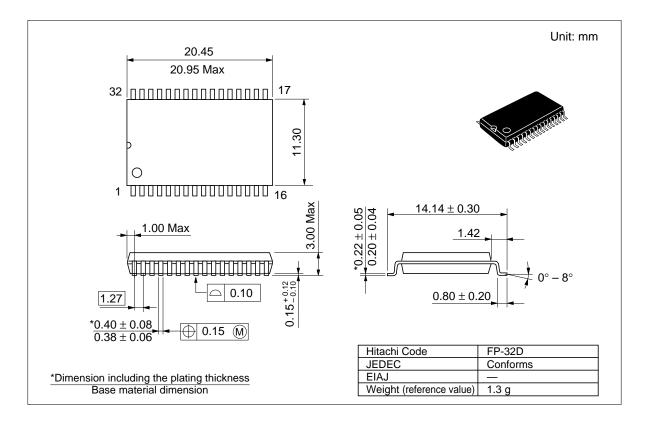


Package Dimensions

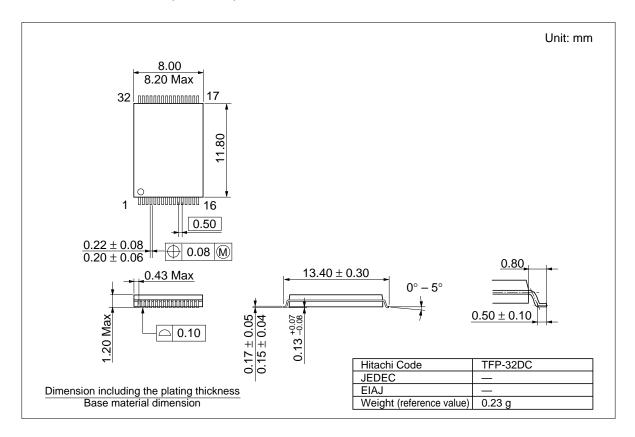
HM628128DLP Series (DP-32)



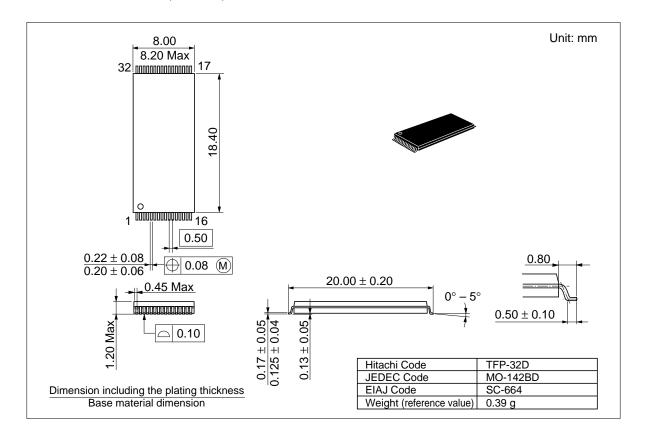
HM628128DLFP Series (FP-32D)



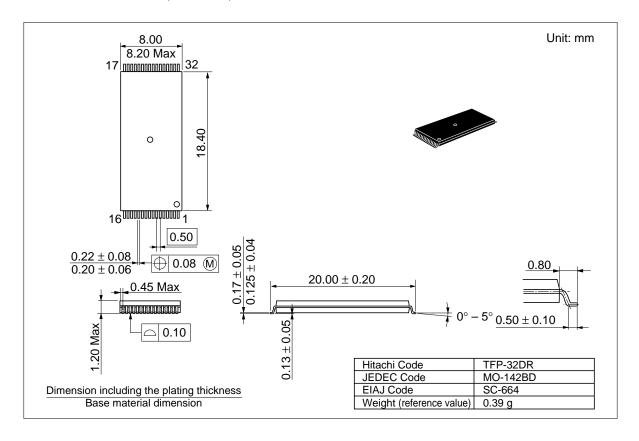
HM628128DLTS Series (TFP-32DC)



HM628128DLT Series (TFP-32D)



HM628128DLR Series (TFP-32DR)



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